



Data acquisition and analysis for the Milano neutrino mass experiment





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In a neutrino mass experiment it is crucial to achieve high energy and time resolutions together with a high statistics. It is also very important to distinguish between real beta decay events and various kind of spurious events. In this poster we describe the VXI-based data acquisition system used during about one year of measurement of t and the software tools employed to analyse the collected data. We consider in particular the event selection by means of Artificial the Neuronal Networks and the pile-up recognition by means of Wiener Filtering. Moreover we give details about the complete procedure to obtain the ¹⁸⁷Re beta spectra. We describe also both the statistical approach applied to obtain the neutrino mass limit and the method to determine the ¹⁸⁷Re lifetime.

1. VXI data acquisition system

• Hardware

▷ A/D converter: Tektronix VX4244 16-channel 16-bit 100 ks/s per channel Trigger: Tektronix VX4286 16-channel analog comparator/interrupter





- T2 executes less



Software

- ▷ Labwindows/CVI
- ▷ multi-threaded acquisition code
- Daq set-up
- ▷ free-running ADC
- trigger time-tags to extract pulses

2. Acquisition configuration





5. Pulse shape analysis

- aim: discriminate between true β and spurious events
- tool: 3-layer Artificial Neuronal Network (ANN) applied to 10 ch. averaged pulses (60 input nodes)





- 6. Pile-up recognition
- aim: resolve two β decays closely spaced in time
- tool: Wiener Filter
- \triangleright time resolution $\Delta t \approx 3 \tau_{rise}$





• pulse digitization \triangleright 2048 samples, 26 μ s time base • one-day measurements (for refrigerator service) • acquisition cycles (see poster U09) \triangleright 25 min X-ray calibration (total rate \approx 10 Hz) \triangleright 2 h pure β acquisition (total rate \approx 1 Hz)

- ▷ every one-day data set must begin and end with a calibration period
- ▷ random records are acquired to build noise power spectra

3. Raw data reduction

• average β pulse S(t) and noise power spectra $\mathcal{N}(\omega)$ generation

• *n-tuple* generation

- 8 channel separation (events with multiplicity > 3 are discarded)
- peak stabilization (gain drift correction) using Mn, Ti and Ca K α peaks
- X-ray and pure β periods separation (see poster U09)
- X-ray spectra calibration using 2nd order polynomials (*see poster U09*)
- pulse shape analysis and pile-up recognition for β spectra generation
- β spectra calibration using X-ray spectra calibration results • total X-ray and β spectra generation • **detector energy response function** evaluation (see poster U09) • β spectra analysis



4. *n*-tuple

U12

- **Optimal Filter (OF)** amplitude
- $\triangleright \mathcal{H}_{OF}(\omega) \propto \mathcal{S}^{*}(\omega) / \mathcal{N}(\omega)$ for maximal signal-to-noise ratio
- Adaptive Filter (AF) amplitude
- $\tau_{\rm rise}$ rise and $\tau_{\rm decay}$ decay times (10%-90%)
- shape parameters
- \triangleright root mean square deviation from $S_{OF}(t) = [\mathcal{H}_{OF}(\omega)S(\omega)]^{-1}$ left (TVL) and right (TVR) of $S_{OF}(t)$ maximum
- \triangleright root mean square deviation from template S(t)
- Artificial Neuronal Network (ANN) output
- amplitude and time delay of secondary pulses as found by Wiener filtering (WF)
- $\vdash \mathcal{H}_{WF}(\omega) \propto \mathcal{S}^{*}(\omega) / (|\mathcal{S}(\omega)|^{2} + |\mathcal{M}(\omega)|^{2})$ transfer function for best least-square estimate of *uncorrupted* signal • source open, source closed and random record tags
- **9.** β spectrum analysis (listen to U02 presentation) • fit function: $f(E) = [N_{\text{theo}}(E, m_v) + N_{\text{pile-up}}(E, m_v) + b(E)] \otimes R(E)$ $P N_{\text{theo}}(E, m_{v})$ first forbidden unique Buhring spectrum $\triangleright N_{\text{pile-up}}(E, m_{v}) = A_{\beta} \Delta t [N_{\text{theo}}(E, m_{v}) \otimes N_{\text{theo}}(E, m_{v})] \text{ pile-up spectrum}$
- b(E) polynomial background spectrum \triangleright free parameters: N_{theo} and $N_{\text{pile-up}}$ normalizations, Q_{β} end-point, b(E) parameters, m_{ν}^2 • estimator: $\Xi^2 \cong 2\sum_i [f_i - y_i - y_i \ln(f_i/y_i)]$ with f_i fit values, y_i measured data • Bayesian approach for non physical regions • f(E) consistency tested varying the fitting interval ($E_{min} \ge 0.7 \text{ keV}, E_{max} \le 5 \text{ keV}$)





7. Detector energy response function

- asymmetric detector energy response function R(E)
- ▷ two symmetric gaussians with equal FWHM,
- \approx 40 eV separation and 4:100 area ratio (*see poster U09*)
- energy response function at β end-point for 8 detector sum spectrum
- creation for each peak of a sum spectrum normalizing the peak area to detector mass and measuring time
- peak FWHMs depend on energy
- $\triangleright \Delta E^2_{\text{FWHM}} = \mathbf{a} + \mathbf{b}E + \mathbf{c}E^2$
- a noise
- **b** thermalization
- c uncorrected gain instabilities ($\approx 2\%$)



• extrapolation of ΔE^2_{FWHM} (*E*) at β spectrum end-point

• for β spectrum fitting: gaussian R(E) with constant ΔE $\triangleright \Delta E = \Delta E_{\text{FWHM}}(Q_{\beta})$

8. Summary of RUN 14 detector performances see poster U11 and listen to presentation U02

detector		1	2	3	5	6	8	9	10	sum
mass [µg]		272	259	280	250	284	282	269	278	2174
<i>Т</i> _{ор} [mК]		104	91	104	107	87	72	97	101	
$R_{ m op}$ [M Ω]		1.3	1.9	1.3	1.2	2.2	4.0	1.6	1.4	
threshold	[eV]	350	350	350	470	350	400	400	700	700
	0 keV	20	19	26	21	22	25	18	24	22
۵ <i>Е</i> _{FWHM} [eV]	1.5 keV	24	23	29	25	26	29	21	29	26
	2.6 keV	26	27	31	29	29	33	25	35	29
τ _{rise} [μs]		440	340	670	590	500	510	430	445	492

10. ¹⁸⁷Re lifetime τ measurement

- from distribution of time intervals Δt between two β decays \triangleright needs only a correction for a \approx 40 ms hardware dead time
- ▷ MC simulation
- $\diamondsuit \leq 1\%$ correction
- $N(\Delta t) = A e^{-r\Delta t}$ where $r \propto 1/\tau$ is the β decay rate



11. Systematic errors on *m*²

• perform fits under different hypotheses $\Rightarrow \Delta m_{\nu}^2 \Rightarrow$ systematic	error ε_{sy}

Quantity	contribution to ε_{sys}		
fit interval [keV[0.9÷4	2.1÷4	
\triangleright alternative resolution functions <i>R(E)</i>	79%	14%	
▲ double gaussian <i>R(E</i>)	68%	6%	
non-constant width R(E)	11%	8%	
b different order polynomials for b(E): 1 st or 2 nd	21%	8%	
\triangleright alternative β spectrum parametrizations		78%	
Total systematic error [eV ²]	90	125	

statistical fluctuations 800 500

 \triangleright best fitting interval: 0.9 \div 4.0 keV (for lowest statistical and systematic errors)